

In the Specification

Please amend paragraph [0002] of the specification as detailed herein:

[0002] This invention relates to a microscope which can be used in a Fourier Transform Infrared (FT-IR) FT-IR spectroscopy. FT-IR microscopes generally operate in conjunction with an FT-IR spectrometer. The IR beam used by the microscope is produced by the spectrometer which also controls the scanning.

Please insert between the paragraphs [0005] and [0006] the following section title of:

Brief Summary Of The Invention

Please insert between the paragraphs [00012] and [00013] the following section title of:

Brief Description Of The Drawing

Please amend paragraph [00013] as detailed herein:

[00013] The invention will be described now by way of example only with particular reference to the accompanying drawing, in which:

FIG. 1 is a block schematic diagrammatic view of an embodiment in accordance with the present invention.

Please insert between the paragraphs [00013] and [00014] the following section title of:

Description Of Preferred Embodiment Of The Invention

Please amend the Abstract of the application as detailed herein:

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Response to Official Action

An FT-IR microscope is operated in association with a scanning spectrometer in such a way that incremental movement of the movable stage of [[5]] the microscope is synchronized with the scans of the scanning spectrometer. This minimizes delays in processing time.